

Reliability Monitoring Results

Quarters: Q1/2023 to Q4/2023

Based on structural similarity

| Supplier | | User Part Number | | | | |
|--|--|-----------------------------|-----------|------------|-----------|--|
| Nexperia B.V. | | NXT4556AUR | | | | |
| Part Description: SIM card interface level translator with enable pin | | | | | | |
| Function Family: NXT Process family: C075 Package family: WLCSP | | | | | | |
| JESD47 Test | Test Conditions | Duration | # Lots | # Quantity | # Rejects | |
| # 1 TEST Pre- and Post-Stress Electrical Test | Tamb = 25 °C | N/A | see below | all parts | see below | |
| # 2 PC Preconditioning | JESD22-A113 MSL 1 | N/A | 32 | 2835 | 0 | |
| # 5a HTOL EFR High Temperature Operating Life Extrinsic | JESD22-A108 Tj = 150°C V _{CCMAX} ≤ V ≤ 1.2*V _{CCMAX} | 48 hours or 168 hours | 252 | 46656 | 0 | |
| # 5b HTOL IFR High Temperature Operating Life Intrinsic | JESD22-A108 Tj = 150°C V _{CCMAX} ≤ V ≤ 1.2*V _{CCMAX} | ≥500 hours | 111 | 8362 | 0 | |
| # 7 TC Temperature Cycling | JESD22-A104 -65 °C to 150°C | ≥500 cycles | 16 | 1288 | 0 | |
| # 9 uHAST / HAST unbiased or biased High Accelerated Stress Test | JESD22-A101 Tamb = 130 °C, RH = 85%, V = V _{CCMAX} | 96 hours | 19 | 1547 | 0 | |

Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above)

Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic (HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Product Family | Package Family | Quantity | Rejects | Extrinsic Failure Rate (PPM) | Intrinsic Failure Rate (FIT) | MTTF (hrs) |
|----------------|----------------|----------|---------|------------------------------|------------------------------|------------|
| NXT | WLCSP | 8362 | 0 | 20 | 0.5 | 2.07 E+09 |